

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10676889	LIAO ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	Mitchell, Jason	2193

## SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
717	106,149-150,151-158	10/25/07	/jm/
708	233	10/25/07	/jm/
712	205-207,219	10/25/07	/jm/
717	106,149-158	8/19/08	/jm/
708	233	8/19/08	/jm/
712/jm/	25-207,219	8/19/08	/jm/

## SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
eDan inventor search	10/25/07	/jm/
east search	10/25/07	/jm/
google search	10/25/07	/jm/
east search	8/19/08	/jm/
east search w/ ltd. class search (see notes)	2/16/09	/jm/
east search w/ ltd. class search (717/106,149-150,151-158 712/205-207,219,225,235)	7/22/09	/jm/
east search w/ ltd class search 717/106,149-158 708/233 712/204-207	12/31/09	/jm/
east search w/ ltd class search 717/106,149-158; 708/233; 712/204-207	7/13/10	/jm/
google search	7/13/10	/jm/

## INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

/JASON MITCHELL/  
Examiner.Art Unit 2193

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